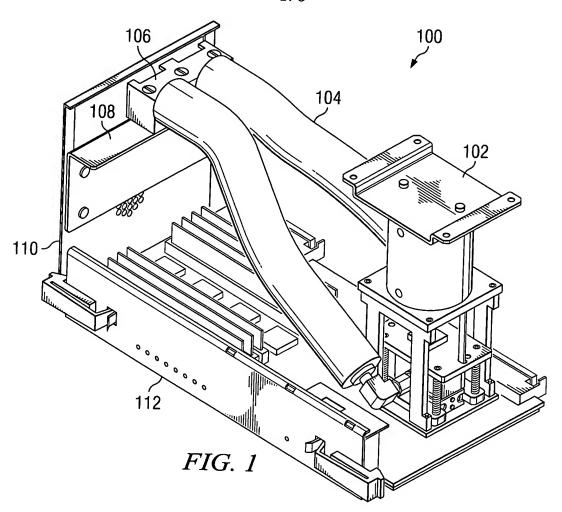
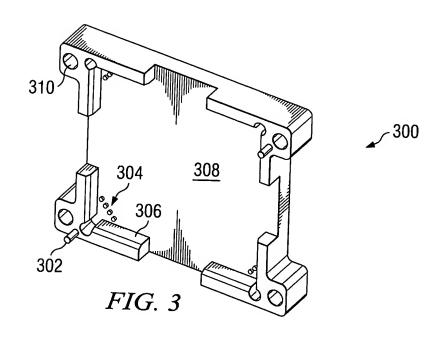
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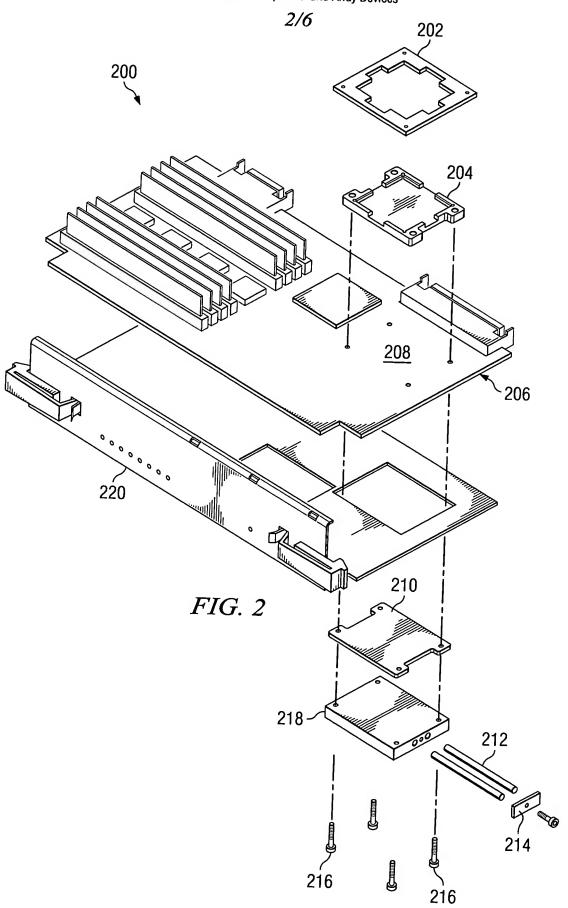
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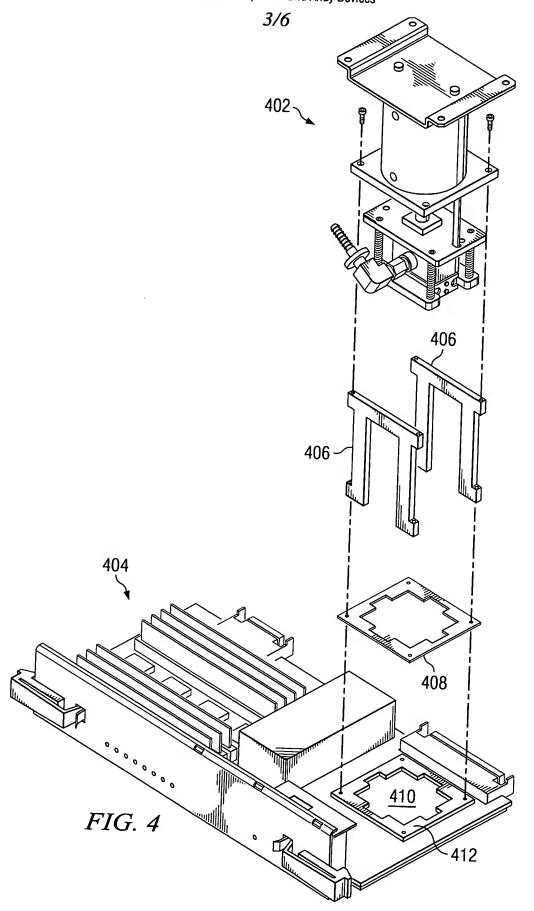
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of Exposed Chip Land Grid Array Devices



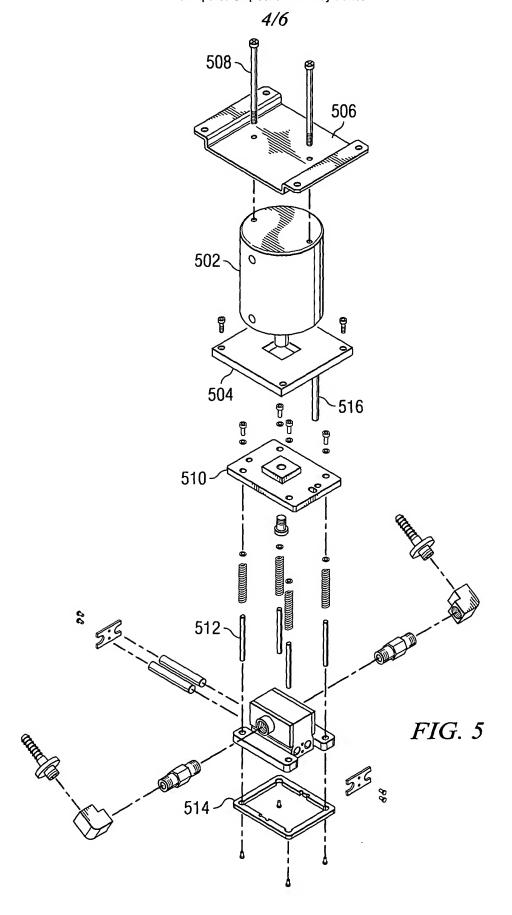
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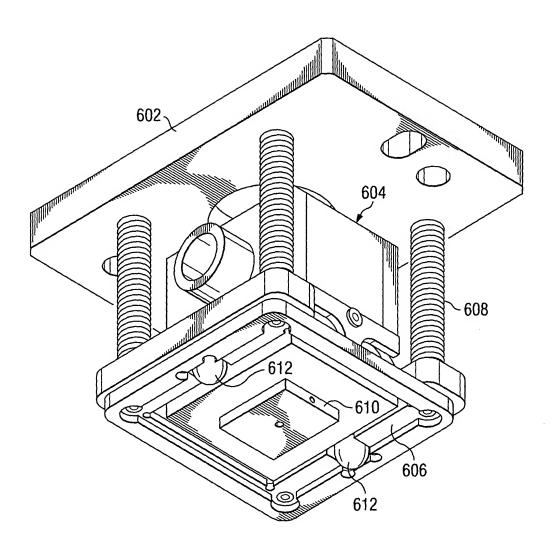
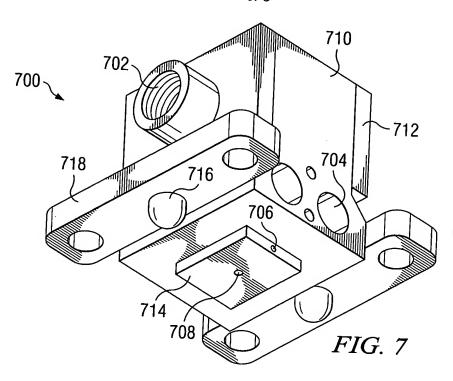


FIG. 6

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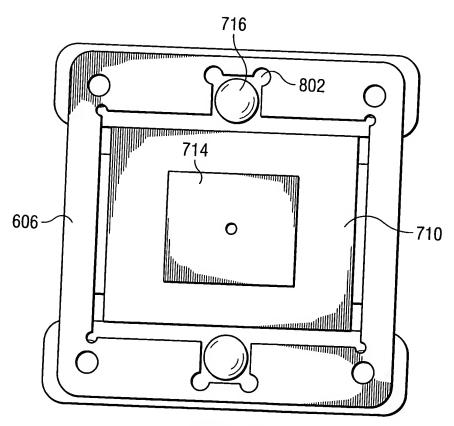


FIG. 8